Packaging technologies for high temperature control electronics

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Introduction

- Module Architecture
- Intermetallic Diffusion
- Polymer Degradation
- Thermomechanical Fatigue

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Component Stress

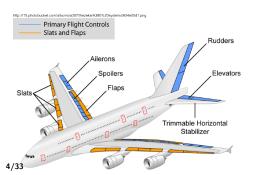
Introduction

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- **Polymer Degradation**
- Thermomechanical Fatigue
- **Component Stress**

CREAM

Compact and Reliable Electronic integrated in Actuators and Motors

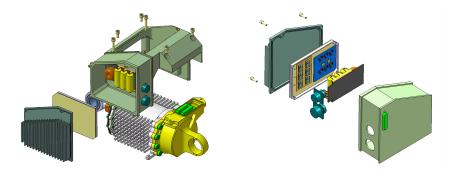
 Future Aircraft will have to meet environmental goals while still remaining competitive—requiring a reduction in size, weight and complexity



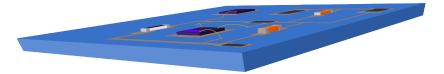
- Removal of all Aircraft hydraulic and Pneumatic systems
- All are replaced with Electro-Mechanical Actuators (EMAs)
- Engines to supply
 Propulsion and Electricity only

High Temperature Electronics

- Reduce size Increase power density
- Reduce complexity Remove cooling from system
- Necessitates high temperature (200°C) electronics



- Chemical reactions, diffusion of particles increase exponentially with temperature
- Larger change in temperature applys more stress on materials



Introduction

Module Architecture

Intermetallic Diffusion

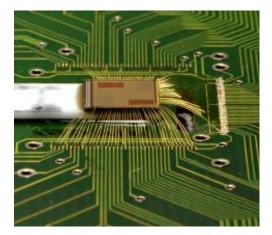
Polymer Degradation

Thermomechanical Fatigue

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Component Stress

"Prometheus"

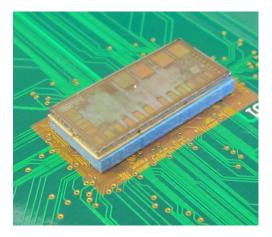


- Silicon on Insulator
- 160 interconnects
- ▶ 5 × 5 mm area
- ▶ 725 µm thick
- Aluminium top metal

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Bare silicon base

"Firebird"



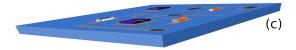
- CMOS Bulk
- 256 interconnects
- ▶ 20 × 9 mm area
- ▶ 725 μ m thick
- Aluminium top metal

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Bare silicon base





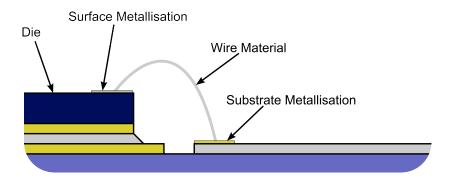


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- Multilayer technology
- Stable at high temperatures

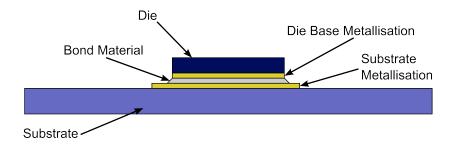
Wire bonds



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- High density of interconnects
- Aluminium wire bonds

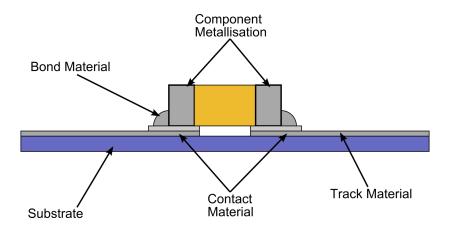
Die Attach



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- No back-side metallisation
- Epoxy adhesive suitable

Discrete Components



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- Conductive adhesive low conductivity
- High lead or lead free solder

Introduction

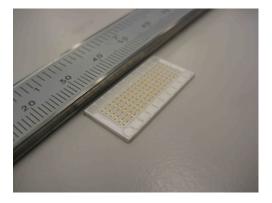
Module Architecture

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Wire bond test vehicle

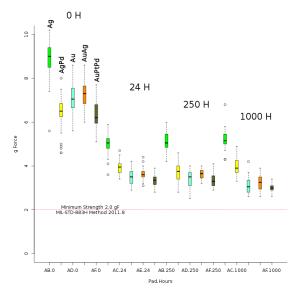


48 25 μ m 99%Al 1%Si wirebonds in daisychain

Type Silver Silver Palladium Gold Gold-Silver Gold-Platinum-Palladium

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High temperature storage and pull tests



- 210°C storage
- Pull tests at 0, 24, 250, 1000 hours
- Silver strong but oxidizes
- All gold containing pads show similar performance

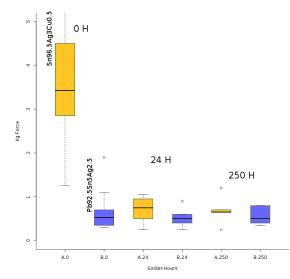
Discrete component test vehicle



5 high temperature capacitors

	Liquidus/
Туре	Solidus
Sn96.5Ag3Cu0.5	220/217
Pb92.5Sn5Ag2.5	310/300

High temperature storage and shear tests



- 210°C storage
- Shear tests at 0, 24, 250 hours
- Fracture through solder for higher shear strengths
- Lower strenth from pad dissolved by solder

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Intermetallic Diffusion

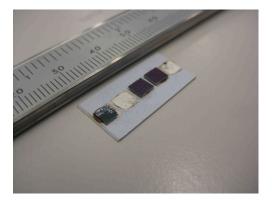
Polymer Degradation

Thermomechanical Fatigue

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Component Stress

Die attach test vehicle

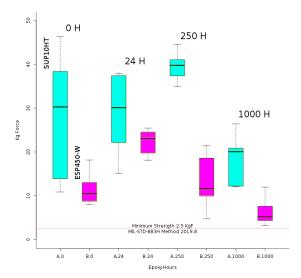


5 silicon dummy dies bonded to substrate

Type SUP10HT ESP450-W Ag filled

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High temperature storage and shear tests



- 210°C storage
- Shear tests at 0, 24, 250, 1000 hours
- Initial increase in strength continued curing
- Later decrease in bond strength breakdown of bonds

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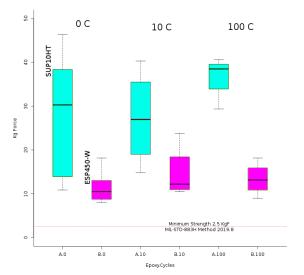
Wire bond temperature cycling and pull tests

0 C 2 Cycles from -20°C to AuPtPd AgPd 180°C ω 10 C Pull tests at 0. 10, 100 cycles ø 100 C g Force Drop in pull 8 strength for all 4 types High gold Minimum Strenath 2.0 aF N MIL-STD-883H Method 2011 8 containing pads worst 0 AB.0 AC.0 AD.0 AE.0 AF.0 AC.10 AE.10 AB.100 AD.100 AF.100 Pad. Cycles

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Die attach temperature cycling and shear tests

- Cycles from -20°C to 180°C
- Shear tests at 0, 10, 100 cycles
- No decernable change
- High flexibility



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Discrete components temperature cycling and shear tests

Sn96.5Aq3Cu0 Cycles from 0 C -20°C to 180°C πt. Shear tests at 10 C 100 C 0, 10, 100 m cycles (g Force No change for N high lead 0 ^{b92.5Sn5Ag2.5} solder Slow decrease in strength for lead free 0 A.0 B.0 A.10 B.10 A.100 B.100 Solder. Cycles

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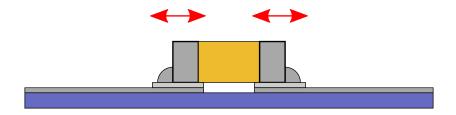
Polymer Degradation

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Component Stress

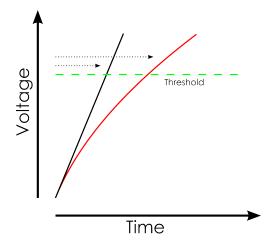


Effect of packaging on component



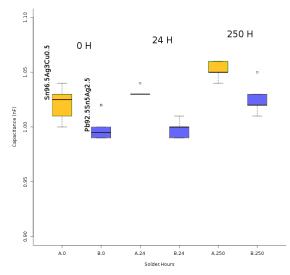
- Package to protect component
- Capacitors sensitive to packaging type

Capacitance Measurement



- Leakage current affects measurement
- Increase in capacitance an indication of leakage
- Simple method for determining damage

Change in capacitance after temperature storage

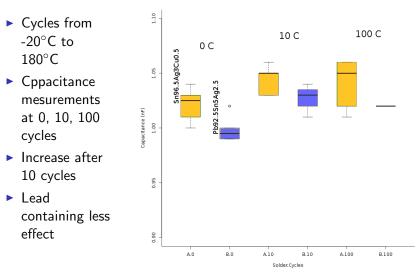


- 210°C storage
- Capacitance measurment at 0, 24, 250 hours
- Increase in capacitance after 250 hours
- High lead less effect than lead free

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Change in capacitance after cycling



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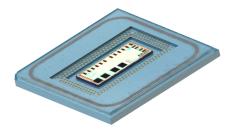
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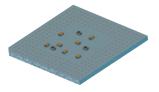
Component Stress



Conclusions



- Epoxy Die Attach
- Aluminium Wire Bonds — Au-Pt-Pd Pads
- High Pb Solder



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Thank you for your attention





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